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Application/Control No.	Applicant(s)/Patent under Reexamination
10/657,797	MOYER ET AL.
Examiner	Art Unit
Daniel Pan	2183

SEARCHED			
Class	Subclass	Date	Examiner
712	4,22	2/10/2006	DP
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
west pgp uspat jpoabs epoabs derwent ibm ieee npl 712/213 int. comp.	2/10/2006	DP
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